

Search Notes

Application/Control No.

10/673,247

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

YAMAKAWA ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	717	5/8/2007	BT
438	722	5/8/2007	BT
438	736	5/8/2007	BT
438	742	5/8/2007	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	5/8/2007	BT